Unit in mm

## TOSHIBA TRANSISTOR SILICON NPN EPITAXIAL PLANAR TYPE

# 2 S C 5 3 1 7

VHF~UHF BAND LOW NOISE AMPLIFIER APPLICATIONS

(CHIP:  $f_T = 16GHz$  series)

Low Noise Figure: NF=1.3dB (f=2GHz) : Ga = 9dB (f = 2GHz)High Gain

## MAXIMUM RATINGS ( $Ta = 25^{\circ}C$ )

CHARACTERISTIC	SYMBOL	RATING	UNIT
Collector-Base Voltage	VCBO	8	V
Collector-Emitter Voltage	$v_{CEO}$	5	V
Emitter-Base Voltage	$V_{EBO}$	1.5	V
Collector Current	$I_{\mathbf{C}}$	20	mA
Base Current	$I_{\mathbf{B}}$	10	mA
Collector Power Dissipation	PC	100	mW
Junction Temperature	$T_j$	125	°C
Storage Temperature Range	$T_{ m stg}$	-55~125	$^{\circ}\mathrm{C}$

 $1.6 \pm 0.2$ 0.8 ± 0.1 1. BASE 2. **EMITTER** 3. COLLECTOR JEDEC EIAJ 2-2H1A TOSHIBA

Weight: 2.4mg

#### MARKING



#### MICROWAVE CHARACTERISTICS (Ta = 25°C)

CHARACTERISTIC	SYMBOL	TEST CONDITION	MIN.	TYP.	MAX.	UNIT
Transition Frequency	${ m f_T}$	$V_{CE}=3V$ , $I_{C}=15mA$	9	_	_	GHz
Insertion (fain	$ S_{21e} ^2$ (1)	$V_{CE}=3V$ , $I_{C}=15mA$ , $f=1GHz$	_	15	_	dB
	$ S_{21e} ^2$ (2)	$V_{CE}$ =3V, $I_{C}$ =15mA, f=2GHz	_	9	_	
Noise Figure $\frac{NF(1)}{NF(2)}$	NF (1)	$V_{CE}$ =3V, $I_{C}$ =5mA, $f$ =1GHz	_	0.9	1.8	dB
	NF (2)	$V_{CE}$ =3V, $I_{C}$ =5mA, $f$ =2GHz	_	1.3	2.2	

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# ELECTRICAL CHARACTERISTICS (Ta = 25°C)

CHARACTERISTIC	SYMBOL	TEST CONDITION	MIN.	TYP.	MAX.	UNIT
Collector Cut-off Current	$I_{CBO}$	$V_{CB} = 10V, I_{E} = 0$	_	_	1	μA
Emitter Cut-off Current	$I_{\mathrm{EBO}}$	$V_{EB}=1V, I_{C}=0$	_	_	1	$\mu$ A
DC Current Gain	$h_{ ext{FE}}$	VCE=3V, IC=15mA	50	_	250	V
Output Capacitance	$C_{ob}$	$V_{CB} = 2.5V, I_{E} = 0, f = 1MHz$	_	0.7	_	pF
Reverse Transfer Capacitance	$\mathrm{c}_{\mathrm{re}}$	(Note)	_	0.5	0.85	pF

Note:  $C_{re}$  is measured by 3 terminal method with Capacitance bridge.

## CAUTION

This device electrostatic sensitivity. Please handle with caution.